

DESCRIPTION

EPG428 is an Electrical Pattern Generator module that plugs into the PARALLEX® Chassis. EPG428 can generate 4 channel electrical data from 1 Gb/s up to 29 Gb/s continuously. A half-rate input clock is required and it can be daisy-chained to the Error detector and additional modules. Therefore it is an ideal solution for 100Gb/s and future 400Gb/s applications.



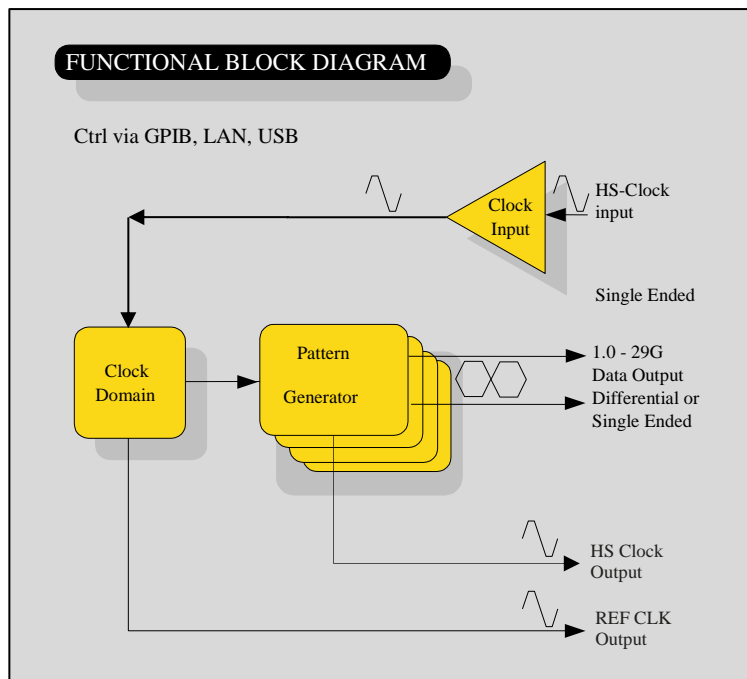
EPG428

PATTERN GENERATOR MODULE PN: L-6001-EP428-1

KEY FEATURES

- Data Rates 1 to 29 Gbps
- 4 channels
- Operates with half rate clock
- Differential Electrical Pattern Generator (K Connector)
- Reference clock output to drive SERDES, CDR that require low speed clock
- PRBS pattern: 9, 15, 31
- Data output polarity swap
- High speed Clock Input and Output
- GPIB/LAN/USB Interface via PARALLEX® Chassis.
- Small size: width 50.8mm (2")

Product Brief



Pattern Generator Module

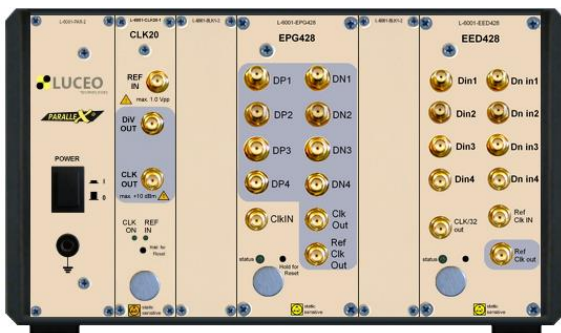
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KEY PERFORMANCE PARAMETERS

PARAMETER	SYMBOL	VALUE	UNIT	NOTE
channels	chNo	4		
Data Rate	DR	1... 29	Gbps	1)
Data Format		NRZ		
PRBS Pattern		9, 15, 31		
Differential Data Output Amplitude	$D_{OutP/N}$	200...800	mV _{pp}	setting range, 3)
Output Jitter (RMS)	J_{rms}	200	fs	Typical, 2)
Single ended Data Output Impedance	Z_{Ose}	50	Ω	Typical
Data Output Termination		AC - coupled		
Clock Input / Output Frequency	F_{Clk}	0.5... 14.5	GHz	
Clock Input / Output Termination		AC - coupled		

Note:

- 1) Output of clock signal is used for daisy chaining additional modules. Maximum daisy chain length is four.
- 2) RJ measured with CLK pattern. Depends on applied clock signal (measured with CLK20-2 Module, RJ=200fs)
- 3) Measured at 1GBd at the static High/ Low level of the signal with de-emphasis=0dB. The eye height at higher data rates might differ.



SYSTEM SOLUTION
clock source, pattern generator, error detector



ELECTRICAL EYE-DIAGRAM
PRBS9, Data Rate = 25 Gbps

XBERT PLATFORM: LETS YOU START SMALL AND GROW

PARALLEX[®] is a low-cost, modular Bit Error Rate Test Platform used for verification and test of up to 29 Gbps optical and electrical chips, sub-assemblies and system designs. *PARALLEX*[®] allows users to perform several BER tests at once using a single clock source. The system is ideal for developers desiring to run simultaneous BER tests on parallel interfaces or multiple independent interfaces. *PARALLEX*[®] is scalable so users can start off with a single channel and add modules to grow the system. Manufacturers can realize great savings by taking advantage of the *PARALLEX*[®] system's scalability to perform parallel testing in volume production environments.

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